## Notice of References Cited Application/Control No. 10/723,159 Examiner Khai M. Nguyen Applicant(s)/Patent Under Reexamination LEE, YONG-HEE Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-4,468,790	08-1984	Hofelt, Martijn H. H.	375/245
	В	US-4,862,169	08-1989	van Bavel et al.	341/143
	С	US-5,030,952	07-1991	Ledzius et al.	341/143
	D	US-5,061,928	10-1991	Karema et al.	341/143
	Ę	US-6,300,890	10-2001	Okuda et al.	341/143
	F	US-6,515,607	02-2003	Liu et al.	341/143
	G	US-4,876,543	10-1989	van Bavel, Nicholas R.	341/143
	Ή	US-4,920,544	04-1990	Endo et al.	375/243
	_	US-5,298,900	03-1994	Mauthe et al.	341/143
	٦	US-5,148,167	09-1992	Ribner, David B.	341/143
	к	US-5,446,460	08-1995	Cabler, Carlin D.	341/143
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Т					

## **NON-PATENT DOCUMENTS**

*	ļ	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.